

Product data sheet

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SI2309CDS-T1-GE3-MS

Semiconductor Compiance

Roms



Features

- -60V,-1.8A, RDS(ON) =200mΩ@VGS = -
- 10V Improved dv/dt capability
- Fast switching
- Green Device Available

Applications

- Motor Drive
- Power Tools
- LED Lighting

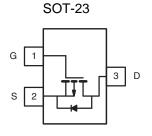
BVDSS	RDSON	ID
-60V	200m Ω	-1.8A

Absolute Maximum Ratings Tc=25°C unless otherwise noted

Symbol	Parameter	Rating	Units
V _{DS}	Drain-Source Voltage	-60	V
V _{GS}	Gate-Source Voltage	±20	V
	Drain Current – Continuous (T _A =25°C)	-1.8	A
D	Drain Current – Continuous (T _A =70°C)	-1.5	A
DM	Drain Current – Pulsed ¹	-8	A
2	Power Dissipation (T _A =25°C)	1.56	W
Po	Power Dissipation – Derate above 25°C	0.012	W/°C
Тѕтс	Storage Temperature Range	-55 to 150	°C
TJ	Operating Junction Temperature Range	-55 to 150	°C

Thermal Characteristics

Symbol	Parameter	Тур.	Max.	Unit
R _{0JA}	eJA Thermal Resistance Junction to ambient		80	°C/W





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Electrical Characteristics (T_J=25 °C, unless otherwise noted)

Off Characteristics

Symbol	Parameter Conditions		Min.	Тур.	Max.	Unit
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V , I _D =-250uA	-60			V
$\triangle BV_{DSS} \triangle T_J$	BV _{DSS} Temperature Coefficient	Reference to 25°C,I₀=-1mA		-0.05		V/°C
	Drain Source Lookana Current	V _{DS} =-60V , V _{GS} =0V , T _J =25°C			-1	uA
I _{DSS} Drain-Source Leakage Current		V _{DS} =-48V , V _{GS} =0V , TJ=125℃			-10	uA
I _{GSS}	Gate-Source Leakage Current	V _{GS} =±20V , V _{DS} =0V			±100	nA

On Characteristics

R _{DS(ON)}	Static Drain-Source On-Resistance	V _{GS} =-10V , I _D =-1.8A		200	300	mΩ
		V _{GS} =-4.5V , I _D =-1.5A		300	400	mΩ
V _{GS(th)}	Gate Threshold Voltage	V _{GS} =V _{DS} , I _D =-250uA		-1.7	-2.5	V
$ riangle V_{GS(th)}$	V _{GS(th)} Temperature Coefficient			5		mV/°C
gfs	Forward Transconductance	V _{DS} =-10V , I _D =-2A		3.5		S

Dynamic and switching Characteristics

Qg	Total Gate Charge ^{2,3}			8.2	
Q _{gs}	Gate-Source Charge ^{2,3}	$V_{\text{DS}}\text{=-}30\text{V}$, $V_{\text{GS}}\text{=-}10\text{V}$, $I_{\text{D}}\text{=-}2\text{A}$		1.8	 nC
Q _{gd}	Gate-Drain Charge ^{2,3}			1.5	
T _{d(on)}	Turn-On Delay Time ^{2,3}			5.2	
Tr	Rise Time ^{2,3}	$V_{\text{DD}}\text{=-}30\text{V}$, $V_{\text{GS}}\text{=-}10\text{V}$, $R_{\text{G}}\text{=}6\Omega$		19	 20
T _{d(off)}	Turn-Off Delay Time ^{2,3}	I _D =-1A		35	 ns
Tf	Fall Time ^{2,3}			10.6	
Ciss	Input Capacitance			425	
Coss	Output Capacitance	V _{DS} =-30V , V _{GS} =0V , F=1MHz		35	 pF
Crss	Reverse Transfer Capacitance			20	
Rg	Gate resistance	V_{GS} =0V, V_{DS} =0V, f=1MHz		17	 Ω

Drain-So						
Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
ls	Continuous Source Current				-1.8	А
lsм	Pulsed Source Current	V _G =V _D =0V , Force Current			-3.6	А
V _{SD}	Diode Forward Voltage	V _{GS} =0V , I _S =-1A , TJ=25℃			-1.2	V

Note :

1. Repetitive Rating : Pulsed width limited by maximum junction temperature.

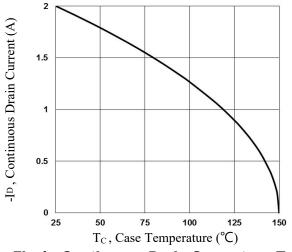
2. The data tested by pulsed , pulse width $\leq 300 us$, duty cycle $\leq 2\%.$

3. Essentially independent of operating temperature.

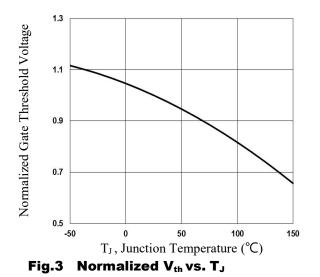


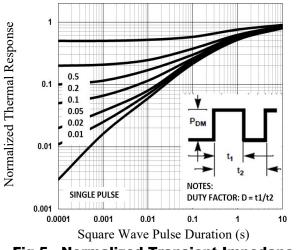
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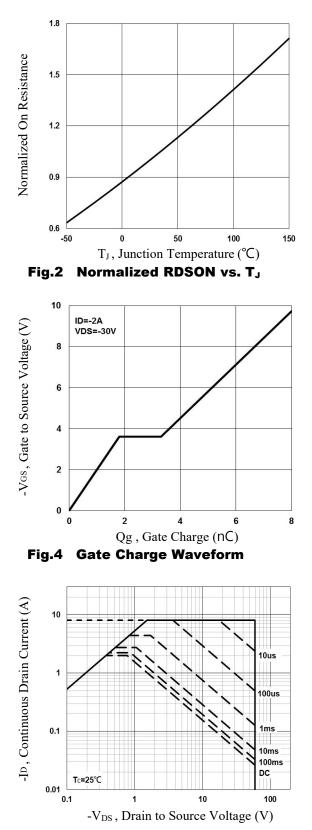


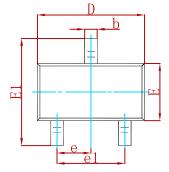
Fig.6 Maximum Safe Operation Area

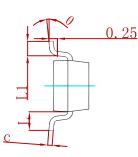


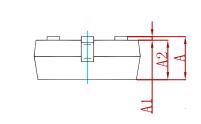
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PACKAGE MECHANICAL DATA

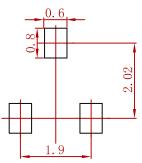






Symbol	Dimensions In Millimeters		Dimension	s in inches
Symbol	Min	Max	Min	Max
А	0.900	1.150	0.035	0.045
A1	0.000	0.100	0.000	0.004
A2	0.900	1.050	0.035	0.041
b	0.300	0.500	0.012	0.020
С	0.080	0.150	0.003	0.006
D	2.800	3.000	0.110	0.118
E	1.200	1.400	0.047	0.055
E1	2.250	2.550	0.089	0.100
е	0.950)TYP	0.037	7 TYP
e1	1.800	2.000	0.071	0.079
L	0.550 REF		0.022	REF
L1	0.300	0.500	0.012	0.020
θ	0°	8°	0°	8°

Suggested Pad Layout



Note:

1.Controlling dimension:in millimeters. 2.General tolerance:± 0.05mm.

3. The pad layout is for reference purposes only.

REEL SPECIFICATION

P/N	PKG	QTY
SI2309CDS-T1-GE3-MS	SOT-23	3000



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